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AI Security and Safety

Guest Editor:

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Deadline for manuscript submissions:

closed (15 March 2024)

Message from the Guest Editor

Dear Colleagues,

In this Special Issue, we aim to bring together researchers from the fields of adversarial machine learning, model robustness, model privacy, and explainable AI to discuss recent research and future directions for AI security, in particular, computer vision and pattern recognition. We invite submissions on any aspect of the security in deep learning systems (particularly computer vision and pattern recognition). We welcome research contributions related to, but not limited to, the following topics:

- Adversarial attacks and defenses for deep learning systems;
- Backdoor attacks and mitigations for deep learning models;
- Model stealing for AI applications and systems;
- Understanding the uncertainty and vulnerabilities of DNNs;
- Deepfake techniques on images and videos;
- Robustness of compact models and systems;
- Privacy-preserved deep learning;
- Explainable AI.











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Editor-in-Chief

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Message from the Editor-in-Chief

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